

**Amendments to the Specification:**

Page 5, paragraph 15, please amend as follows:

The test package 18 is mounted to a conventional test socket 20. As is well known in the art, the test socket 20 has pass-through connections 22 that allow the pads ~~13-11~~ of the test package 18 to connect to another device or circuit board. In a preferred embodiment of the present invention, a gang testing board 12 is provided on which the test package 18 is mounted using the test socket 20.

Page 5, paragraph 16, please amend as follows:

This particular gang testing board 12 includes wire fingers ~~22-24~~ and at least two edge card connectors; sectioned edge card connector 14 and shorted edge card connector 16 mounted along the sides of the gang testing board 12. According to the present invention, the wire fingers 24 are coupled to the pads of the test package 18 via the test socket 20, such that multiple gangs of positively biased daisy chain loops 30 are formed and multiple gangs of negatively biased daisy chain loops 32 are formed. As shown, adjacent gangs 30 and 32 formed by the wire fingers 24 are oppositely biased.